Sheet 1 of 2					(
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE				ATTY DOCKET NO. 2001_1227	,			-	
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(Use several sheets if necessary) Date Submitted to PTO: August 30, 2001				FILING DATE August 30, 2001			GR UP 1763		
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 2 of 2										
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